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High-Resolution OLED Display Driver IC Testing: Trends and Challenges

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Agenda

Introduction

- **Display Technologies and Trends**
- OLED Advantages, Disadvantages, and Challenges
- OLED DDIC Test Key Concepts
- Addressing Technical and Economic Challenges of OLED DDIC Test







Cohu Introduction



The Evolution of Cohu – 50+ Years of Expertise





Market and Technology Leadership

Strong position in each business vertical



(1) Leading sopplier of Ki Front-Lind test equipment,
 (2) Service business of Cohu systems
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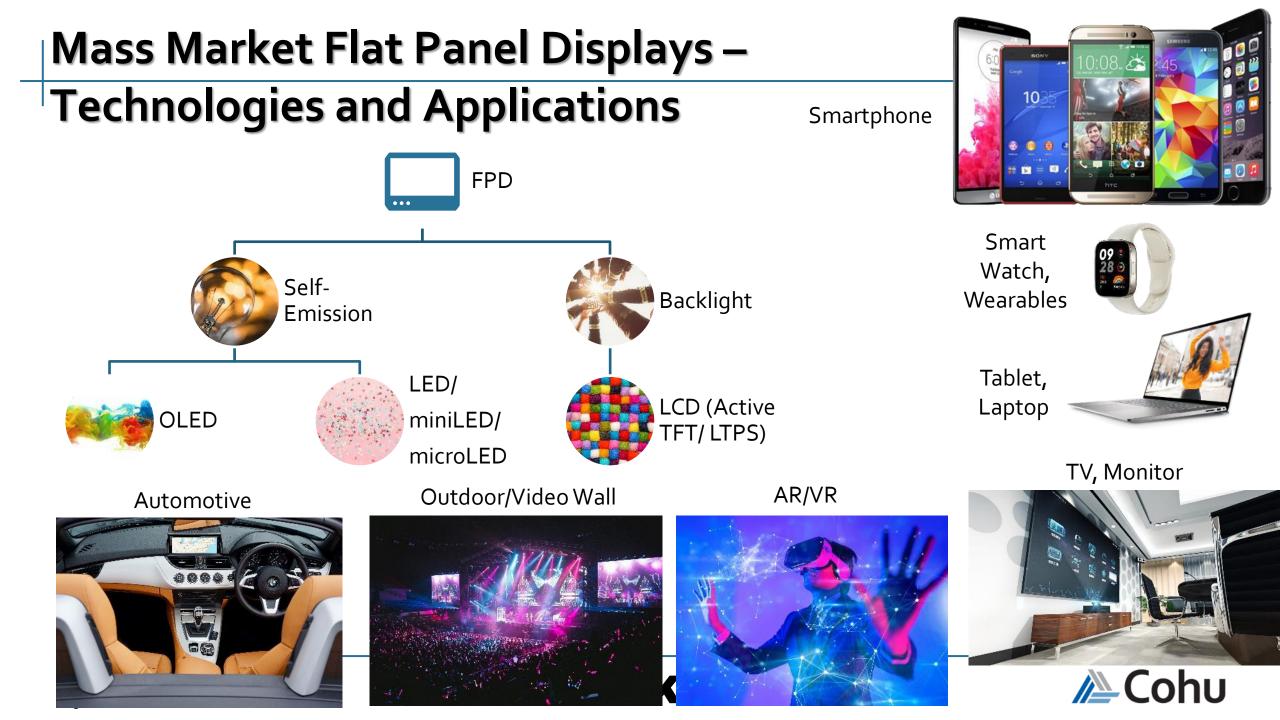




Display Technologies and Trends

OLED Advantages and Disadvantages





Modern Flat Panel Display Technologies

LCD (Liquid Crystal Display)

- Tiny rod-shaped molecules change orientation in the presence of electric current
- Angle of the tiny rod-shaped determine amount of light passing through
- Electrode pair for each color dot is controlling the liquid crystal angle
- White LED backlight, Combination of 3 color filter provide actual color

QLED (Quantum Dot LCD with LED Backlight)

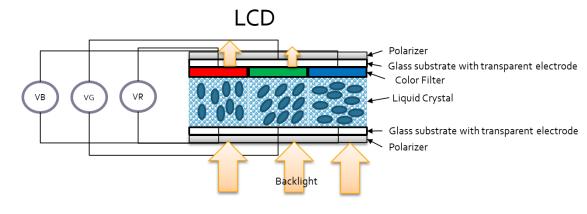
- Tiny crystals emit color when you shine blue or ultraviolet light on them
- Use a blue LED backlight instead of white
- Emerging OLED backlight, transition from miniLED

OLED (Organic Light Emitting Diode)

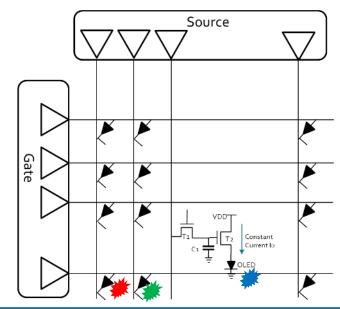
- Using organic carbon-based compounds, OLEDs are mass fabricated on plastic sheets
- OLEDs emit light in response to an electric current; no backlight
- Current flow through transistor is control by capacitor voltage
- RGB OLED vs White OLED with Color Filter (cost down)

MiniLED, MicroLED, and More

- MiniLED Tiny discrete LEDs, used for backlighting of LCD panel or to make large scale display pixels
- MicroLED Microscopic discrete LEDs to create the entire display pixels
- MicroOLED Tiny High PPI OLED for VR
- Liquid Crystal on Silicon Tiny High PPI LCD for AR/VR



OLED





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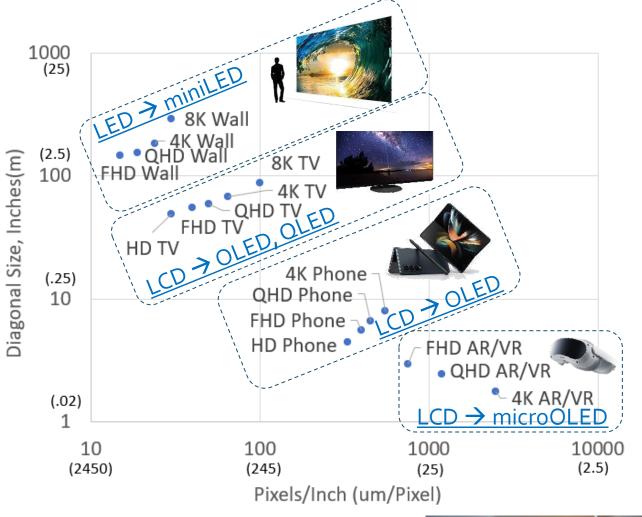
OLED Display Trends

Benefits over LCD

- Self-light emission → Wide viewing angle, improved contrast and color gamut, lower power, faster response time
- Eliminates use of backlight module → Ultrathin design
- Flexible → Innovative form factors

Disadvantages

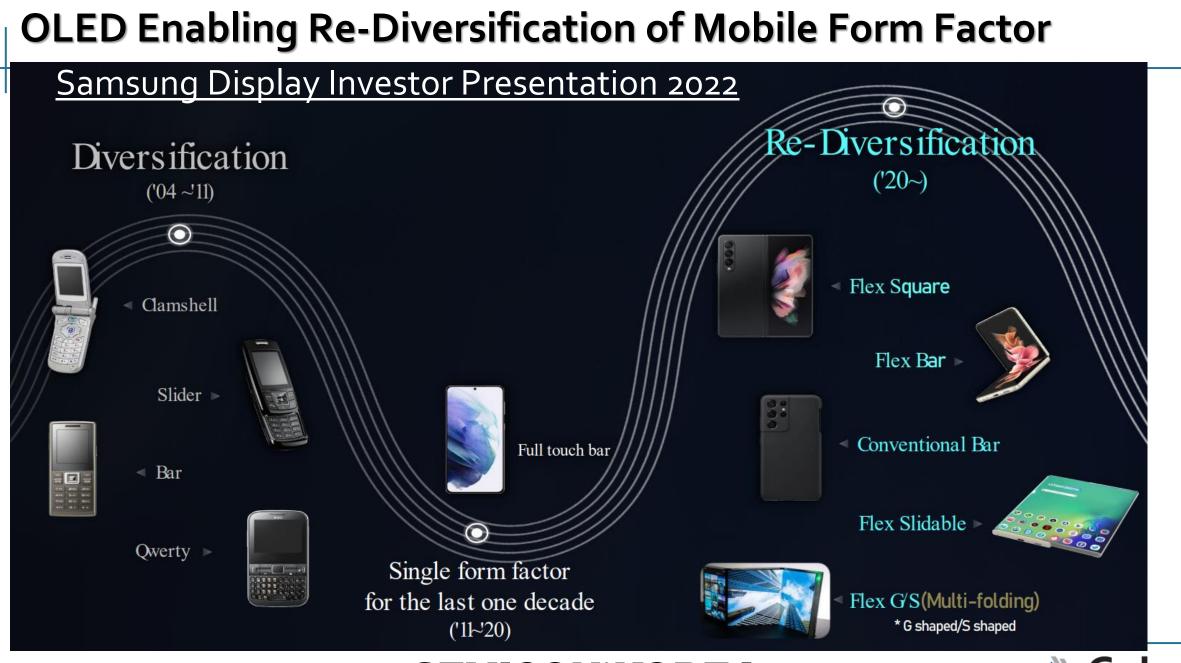
- OLED display has a higher cost than TFT-LC mainly due to yield issues
- Long-term reliability concerns
- OLED becoming dominant in high-end phones and TV, smartwatch, AR/VR
- Emerging in high-end automotive











Source:https://images.samsung.com/is/content/samsung/assets/global/ir/do Pagentong_Investor_Presentation_DP_2022_v1.pdf

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/ Cohu



OLED DDIC Test Key Concepts

Addressing Technical and Economic Challenges



Mobile DDIC Structure and Test Requirements

□ Highly Integrated IC

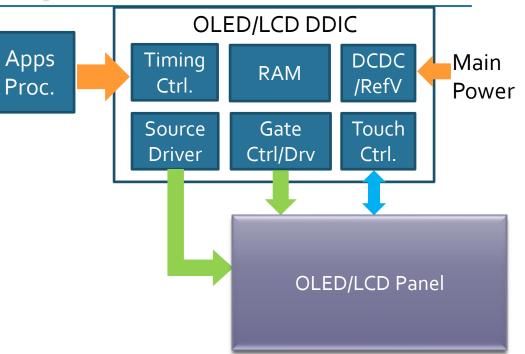
- High Speed Digital Reciever: MIPI D-Phy/C-Phy, with HS/LP modes, Speeds increasing to 6Gsym/s+ → High speed digital instrument
- Timing Controller (TCON), Scaler, RAM → Full digital test capability
- DC-DC, LDO, Gamma Reference Supplies → Full analog/power test capability
- Source and Gate Drivers → Specialized high channel count DDIC instrument with high voltage digitizer/comparator/TMU
- Touch Sensor Integration → Additional mixed-signal instrumentation requirements

□ Usually Chip-on-Glass (COG) or Chip-on-Plastic (COP)

- Requires known-good die → comprehensive testing at probe, incl. full mixed-signal, power/trim, high-speed digital
- Chip-on-Film (COF) sometimes used bezelless display
- → Requires expertise in test cell integration with probers and COF handler

Ultra-High Pin-Counts and Multi-Site Cost Down

- Basic HD Mobile device: 720 columns * R/G/B = 2160 channels
- Higher resolution devices have even more channels
- → Requires high density, scalable, cost-effective test solution







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TV/Monitor Panel DDIC

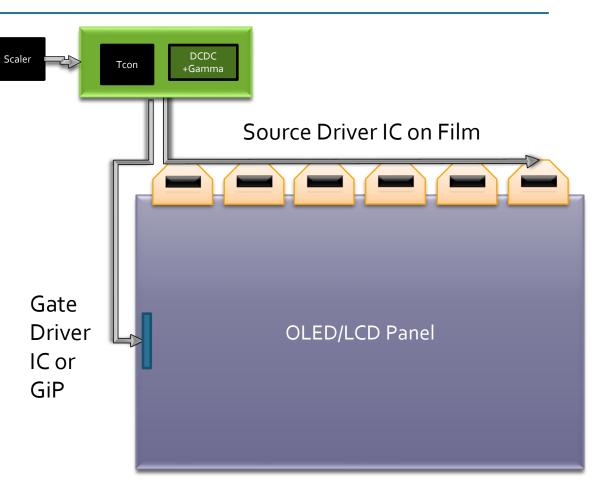
Separate IC for TCON, DC-DC, Gamma VRef, Gate Driver, Source Driver

- Multiple Source Driver ICs used to achieve higher resolution and drive large panel
- HDR Wide Color Gamut driving higher resolution Source Drivers
- Higher Brightness OLED driving higher Source drive current
- High Speed SerDes Interface: 3-4Gsym/s, moving to 6Gsym/s+

Gource Driver ICs are usually on COF packages.

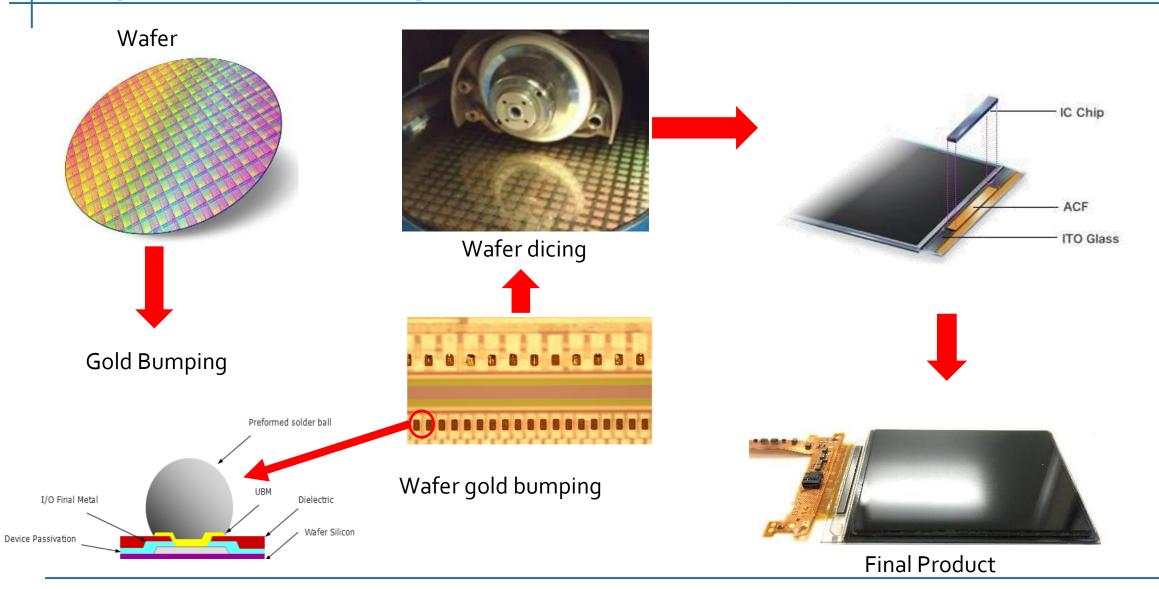
- Fold and hide on the backside of the panel
- Also provides another layer of fanout of IC signals to larger pitch I/O on panel
- □ Key Test Challenges/Requirements
 - Specialized DDIC instrument
 - High voltage digitizer, comparator, TMU; Enhanced accuracy for HDR and higher load capability for brighter OLEDs
 - High Speed Digital SerDes Instrument
 - COF Package extremely sensitive to leakage <<10nA
 - Probe and COF Test Cell Integration Expertise





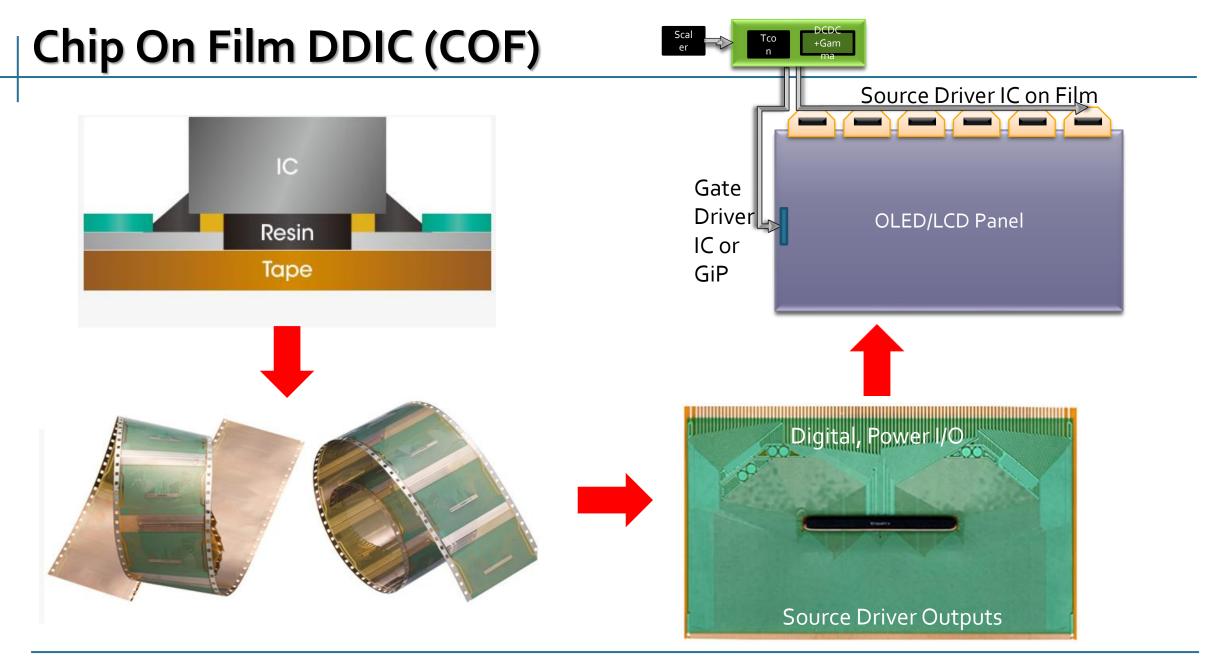


Chip On Glass/Chip On Plastic (COG, COP)





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OLED DDIC – Addressing Economic Challenges

OLED becoming dominant in high end phones and TV, smart watch, AR/VR... ...BUT, significant cost gap versus LCD persists

Essential Elements for Cost Reduction and Risk Management

- Complex IC with extreme pin count requires aggressive multi-site strategy → Need scalable test system that can meet multi-site requirements
- Increasing integration and modularization, such as OLED TDDI and AR/VR micro-display → Need flexible system that can handle full range of DDIC, analog/power, digital, mixed-signal, even wireless requirements
- Automotive OLED driving need for high reliability and tri-temp test → Test partner must have extensive experience with tri-temp and data analytics for automotive
- Continual focus on test time reduction → High throughput tester architecture and optimized test IP
- Fast-moving display market landscape requires continual focus on fast time to market
 Structured approach to getting DDIC to market quickly to maximize profit





Cohu Diamondx Tester – Key Benefits





20 Slot

40 Slot

5 Slot

Low Cost

- Air-Cooled, Small Footprint
- Scalable Infrastructure, from Zero Footprint to Massive Multi-Site
- Leading-Edge Throughput and Multi-site Efficiency

□ Wide Range of Capability

- Display Driver IC
- Wireless: 5G, Wi-Fi 6/7, PA/FEM, IoT
- PMIC, BMU, Automotive
- Logic: MCU, TCON, AP, DTV
- SiP/MCM, Sensor, MEMS
- Fastest Time To Market
 - Flexible Test IP and Powerful Debug Tools





Accelerating Time To Yield And Test Cell Productivity

Cohu one-stop-shop for leading-edge solutions in test & inspection

